Quad buffer/line driver; 3-state Rev. 4 — 1 December 2015

**Product data sheet** 

#### 1. **General description**

The 74HC126; 74HCT126 is a quad buffer/line driver with 3-state outputs controlled by the output enable inputs (nOE). A LOW on nOE causes the outputs to assume a high-impedance OFF-state. Inputs include clamp diodes. This enables the use of current limiting resistors to interface inputs to voltages in excess of V<sub>CC</sub>.

#### 2. Features and benefits

- Inverting outputs
- Complies with JEDEC standard no. 7A
- Input levels:
  - For 74HC126: CMOS level
  - For 74HCT126: TTL level
- ESD protection:
  - HBM JESD22-A114F exceeds 2000 V
  - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from -40 °C to +85 °C and -40 °C to +125 °C

#### **Ordering information** 3.

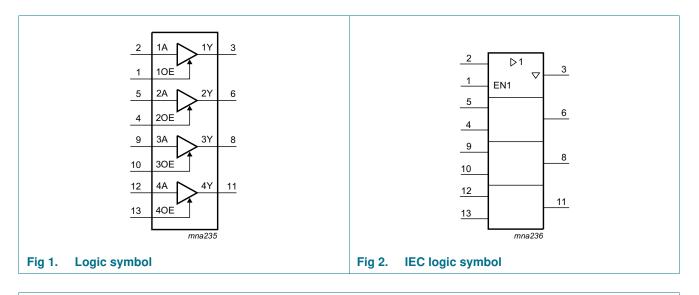
#### Table 1. **Ordering information**

Type number	Package	Package								
	Temperature range	Name	Description	Version						
74HC126D	–40 °C to +125 °C	SO14	plastic small outline package; 14 leads;	SOT108-1						
74HCT126D			body width 3.9 mm							
74HC126DB	–40 °C to +125 °C	SSOP14	plastic shrink small outline package; 14 leads;	SOT337-1						
74HCT126DB			body width 5.3 mm							
74HC126PW	–40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads;	SOT402-1						
74HCT126PW			body width 4.4 mm							



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## 4. Functional diagram



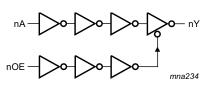
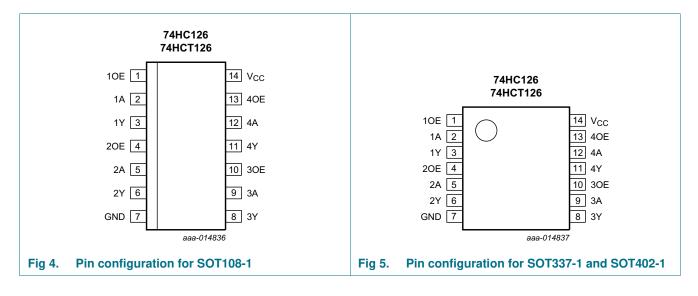


Fig 3. Logic diagram (one buffer/line driver)

# 5. Pinning information



### 5.1 Pinning

### 5.2 Pin description

Table 2.     Pin description									
Symbol	Pin	Description							
10E, 20E, 30E, 40E	1, 4, 10, 13	data enable input (active HIGH)							
1A, 2A, 3A, 4A	2, 5, 9, 12	data input							
1Y, 2Y, 3Y, 4Y	3, 6, 8, 11	data output							
GND	7	ground (0 V)							
V <sub>CC</sub>	14	supply voltage							

## 6. Functional description

#### Table 3.Function table<sup>[1]</sup>

	Input	Output
nOE	nA	nY
Н	L	L
Н	Н	Н
L	X	Z

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

## 7. Limiting values

#### Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>CC</sub>	supply voltage			-0.5	+7	V
I <sub>IK</sub>	input clamping current	$V_{\rm I} < -0.5$ V or $V_{\rm I} > V_{\rm CC}$ + 0.5 V	<u>[1]</u>	-	±20	mA
I <sub>OK</sub>	output clamping current	$V_O < -0.5$ V or $V_O > V_{CC}$ + 0.5 V	<u>[1]</u>	-	±20	mA
lo	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$		-	±35	mA
I <sub>CC</sub>	supply current			-	70	mA
I <sub>GND</sub>	ground current			-70	-	mA
T <sub>stg</sub>	storage temperature			-65	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb} = -40 \text{ °C to } +125 \text{ °C}$				
		SO14 and (T)SSOP14 packages	[2]	-	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] For SO14 package: P<sub>tot</sub> derates linearly with 8 mW/K above 70 °C. For (T)SSOP14 packages: P<sub>tot</sub> derates linearly with 5.5 mW/K above 60 °C.

# 8. Recommended operating conditions

#### Table 5. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	•	74HC126			74HCT126		
			Min	Тур	Max	Min	Тур	Max	
V <sub>CC</sub>	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
VI	input voltage		0	-	V <sub>CC</sub>	0	-	V <sub>CC</sub>	V
Vo	output voltage		0	-	V <sub>CC</sub>	0	-	V <sub>CC</sub>	V
T <sub>amb</sub>	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t / \Delta V$	input transition rise and fall rate	$V_{CC} = 2.0 V$	-	-	625	-	-	-	ns/V
		$V_{CC} = 4.5 V$	-	1.67	139	-	1.67	139	ns/V
		$V_{CC} = 6.0 V$	-	-	83	-	-	-	ns/V

# 9. Static characteristics

#### Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	T <sub>ar</sub>	<sub>nb</sub> = 25	°C		⊧ –40 °C 85 °C	T <sub>amb</sub> = −40 °C to +125 °C		Unit
			Min	Тур	Мах	Min	Max	Min	Max	
74HC126	5								1	
VIH	HIGH-level	V <sub>CC</sub> = 2.0 V	1.5	1.2	-	1.5	-	1.5	-	V
	input voltage	V <sub>CC</sub> = 4.5 V	3.15	2.4	-	3.15	-	3.15	-	V
		V <sub>CC</sub> = 6.0 V	4.2	3.2	-	4.2	-	4.2	-	V
V <sub>IL</sub>	LOW-level	V <sub>CC</sub> = 2.0 V	-	0.8	0.5	-	0.5	-	0.5	V
	input voltage	$V_{CC} = 4.5 V$	-	2.1	1.35	-	1.35	-	1.35	V
		V <sub>CC</sub> = 6.0 V	-	2.8	1.8	-	1.8	-	1.8	V
0.1	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_{O} = -20 \ \mu A; V_{CC} = 2.0 \ V$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_{O} = -20 \ \mu A; V_{CC} = 4.5 \ V$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -20 \ \mu A; V_{CC} = 6.0 \ V$	5.9	6.0	-	5.9	-	5.9	-	V
		$I_{O} = -6.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.98	4.32	-	3.84	-	3.7	-	V
		$I_{O} = -7.8 \text{ mA}; V_{CC} = 6.0 \text{ V}$	5.48	5.81	-	5.34	-	5.2	-	V
V <sub>OL</sub>	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_{O} = 20 \ \mu A; V_{CC} = 2.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_{O} = 20 \ \mu A; V_{CC} = 4.5 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_{O} = 20 \ \mu A; V_{CC} = 6.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_{O} = 6.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	0.15	0.26	-	0.33	-	0.4	V
		$I_{O} = 7.8 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	0.16	0.26	-	0.33	-	0.4	V
I	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 6.0$ V	-	-	±0.1	-	±1.0	-	±1.0	μA
I <sub>OZ</sub>	OFF-state output current		-	±0.5	-	±5.0	-	±10	-	μA

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Quad buffer/line driver; 3-state

Table 6.	Static	characteristics	continued
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At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	T <sub>ar</sub>	<sub>nb</sub> = 25	°C		: –40 °C 85 °C	T <sub>amb</sub> = −40 °C to +125 °C		Unit
			Min	Тур	Max	Min	Max	Min	Max	
I <sub>CC</sub>	supply current		-	-	8.0	-	80	-	160	μA
Cı	input capacitance		-	3.5	-	-	-	-	-	pF
74HCT12	26									
V <sub>IH</sub>	HIGH-level input voltage	$V_{CC} = 4.5 V \text{ to } 5.5 V$	2.0	1.6	-	2.0	-	2.0	-	V
V <sub>IL</sub>	LOW-level input voltage	$V_{CC} = 4.5 V \text{ to } 5.5 V$	-	1.2	0.8	-	0.8	-	0.8	V
V <sub>OH</sub>	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
(	output voltage	I <sub>O</sub> = -20 μA	4.4	4.5	-	4.4	-	4.4	-	V
		I <sub>O</sub> = -6.0 mA	3.98	4.32	-	3.84	-	3.7	-	V
V <sub>OL</sub>	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I <sub>O</sub> = 20 μA	-	0	0.1	-	0.1	-	0.1	V
		l <sub>O</sub> = 6.0 mA	-	0.16	0.26	-	0.33	-	0.4	V
I	input leakage current	$V_{I} = V_{CC}$ or GND; $V_{CC} = 5.5$ V	-	-	±0.1	-	±1.0	-	±1.0	μA
I <sub>OZ</sub>	OFF-state output current		-	-	±0.5	-	±5.0	-	±10	μA
I <sub>CC</sub>	supply current		-	-	8.0	-	80	-	160	μA
ΔI <sub>CC</sub>	additional supply current	per input pin; $I_0 = 0 A$ ; $V_I = V_{CC} - 2.1 V$ ; other inputs at $V_{CC}$ or GND; $V_{CC} = 4.5 V$ to 5.5 V; nA, nOE inputs	-	100	360	-	450	-	490	μΑ
Cı	input capacitance		-	3.5	-	-	-	-	-	pF

# **10. Dynamic characteristics**

#### Table 7. Dynamic characteristics

 $GND = 0 V; C_L = 50 pF;$  for test circuit, see <u>Figure 8</u>.

Symbol	Parameter	Conditions	Tar	<sub>nb</sub> = 25	°C	T <sub>amb</sub> = -40 °	Unit	
			Min	Тур	Max	Max (85 °C)	Max (125 °C)	
74HC126	5							
t <sub>pd</sub>	propagation delay	nA to nY; see Figure 6	[					
		V <sub>CC</sub> = 2.0 V	-	30	100	125	150	ns
		V <sub>CC</sub> = 4.5 V	-	11	20	25	30	ns
		V <sub>CC</sub> = 5.0 V; C <sub>L</sub> = 15 pF	-	9	-	-	-	ns
		V <sub>CC</sub> = 6.0 V	-	9	17	21	26	ns

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Symbol	Parameter	Conditions		Tar	<sub>nb</sub> = 25	°C	T <sub>amb</sub> = -40 °	C to +125 °C	Unit
				Min	Тур	Max	Max (85 °C)	Max (125 °C)	
t <sub>en</sub>	enable time	nOE to nY; see Figure 7	[1]						
		V <sub>CC</sub> = 2.0 V		-	41	125	155	190	ns
		$V_{CC} = 4.5 V$		-	15	25	31	38	ns
		$V_{\rm CC} = 6.0 \ V$		-	12	21	26	32	ns
t <sub>dis</sub>	disable time	nOE to nY; see Figure 7	[1]						
		V <sub>CC</sub> = 2.0 V		-	41	125	155	190	ns
		V <sub>CC</sub> = 4.5 V		-	15	25	31	38	ns
		V <sub>CC</sub> = 6.0 V		-	12	21	26	32	ns
tt	transition time	see Figure 6	[1]						
		V <sub>CC</sub> = 2.0 V		-	14	60	75	90	ns
		V <sub>CC</sub> = 4.5 V		-	5	12	15	18	ns
		V <sub>CC</sub> = 6.0 V		-	4	10	13	15	ns
C <sub>PD</sub>	power dissipation capacitance	per package; V <sub>I</sub> = GND to V <sub>CC</sub>	[2]	-	23	-	-	-	pF
74HCT12	26						1	1	
t <sub>pd</sub>	propagation delay	nA to nY; see Figure 6	<u>[1]</u>						
		V <sub>CC</sub> = 4.5 V		-	14	24	30	36	ns
		$V_{CC} = 5.0 \text{ V}; \text{ C}_{L} = 15 \text{ pF}$		-	11	-	-	-	ns
t <sub>en</sub>	enable time	nOE to nY; see Figure 7; $V_{CC} = 4.5 V$	<u>[1]</u>	-	13	25	31	38	ns
t <sub>dis</sub>	disable time	nOE to nY; see Figure 7; $V_{CC} = 4.5 V$	[1]	-	18	28	35	42	ns
t <sub>t</sub>	transition time	$V_{CC} = 4.5 \text{ V}; \text{ see } \frac{\text{Figure 6}}{1000}$	[1]	-	5	12	15	18	ns
C <sub>PD</sub>	power dissipation capacitance	per package; V <sub>I</sub> = GND to V <sub>CC</sub> – 1.5 V	[2]	-	24	-	-	-	pF

# Table 7.Dynamic characteristics ... continuedGND = 0 V; $C_L = 50$ pF; for test circuit, see Figure 8.

[2]  $C_{PD}$  is used to determine the dynamic power dissipation (P<sub>D</sub> in  $\mu$ W).

 $P_{D} = C_{PD} \times V_{CC}^{2} \times f_{i} \times N + \Sigma(C_{L} \times V_{CC}^{2} \times f_{o}) \text{ where:}$ 

 $f_i$  = input frequency in MHz;

 $f_o$  = output frequency in MHz;

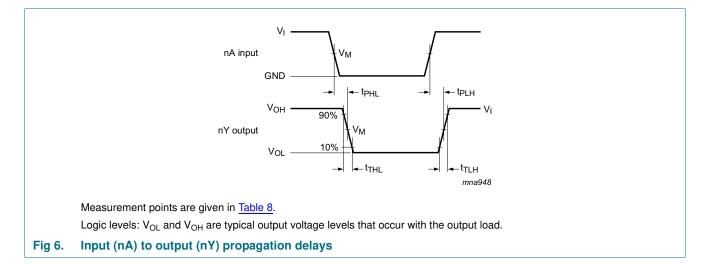
 $C_L$  = output load capacitance in pF;

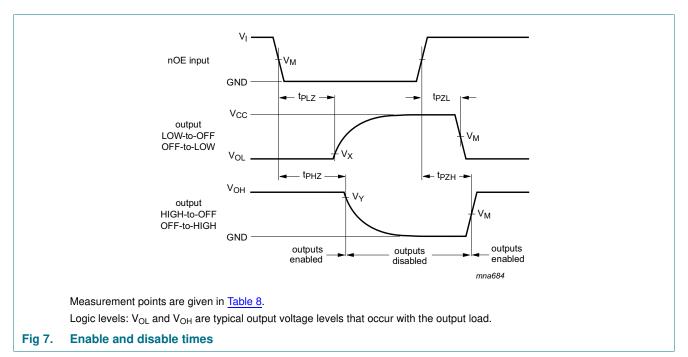
 $V_{CC}$  = supply voltage in V;

N = number of inputs switching;

 $\Sigma(C_L \times V_{CC}^2 \times f_0)$  = sum of outputs.

# 11. Waveforms and test circuit





#### **Measurement points** Table 8.

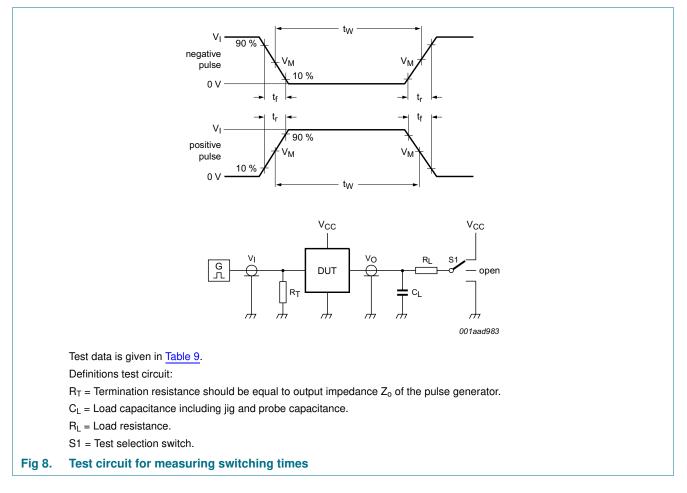
Туре	Input	Output						
	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>				
74HC126	0.5V <sub>CC</sub>	0.5V <sub>CC</sub>	0.1V <sub>CC</sub>	0.9V <sub>CC</sub>				
74HCT126	1.3 V	1.3 V	0.1V <sub>CC</sub>	0.9V <sub>CC</sub>				

74HC\_HCT126 **Product data sheet** 

### **NXP Semiconductors**

# 74HC126; 74HCT126

### Quad buffer/line driver; 3-state

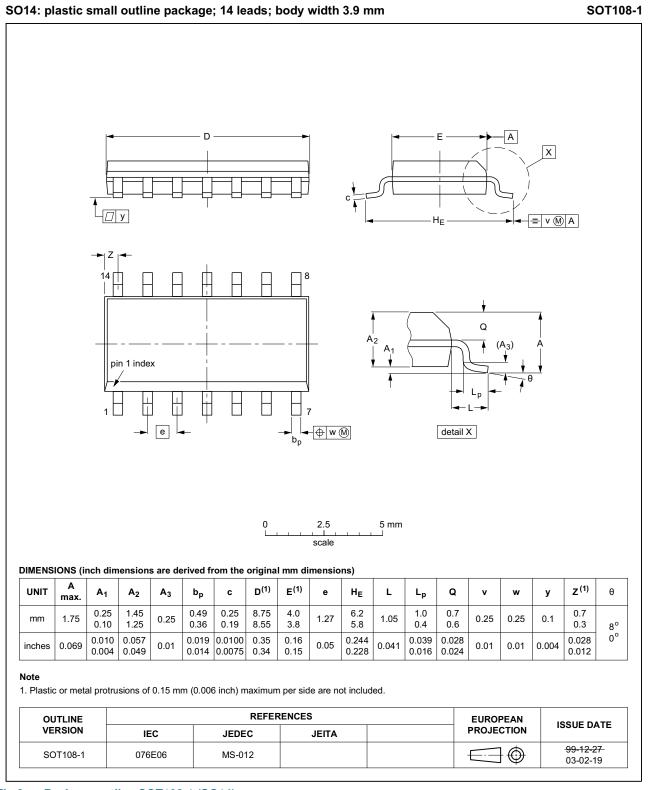


#### Table 9. Test data

Туре	Input		Load		S1 position		
	VI	t <sub>r</sub> , t <sub>f</sub>	CL	RL	t <sub>PHL</sub> , t <sub>PLH</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
74HC126	V <sub>CC</sub>	6 ns	15 pF, 50 pF	1 kΩ	open	GND	V <sub>CC</sub>
74HCT126	3 V	6 ns	15 pF, 50 pF	1 kΩ	open	GND	V <sub>CC</sub>

Quad buffer/line driver; 3-state

## 12. Package outline



#### Fig 9. Package outline SOT108-1 (SO14)

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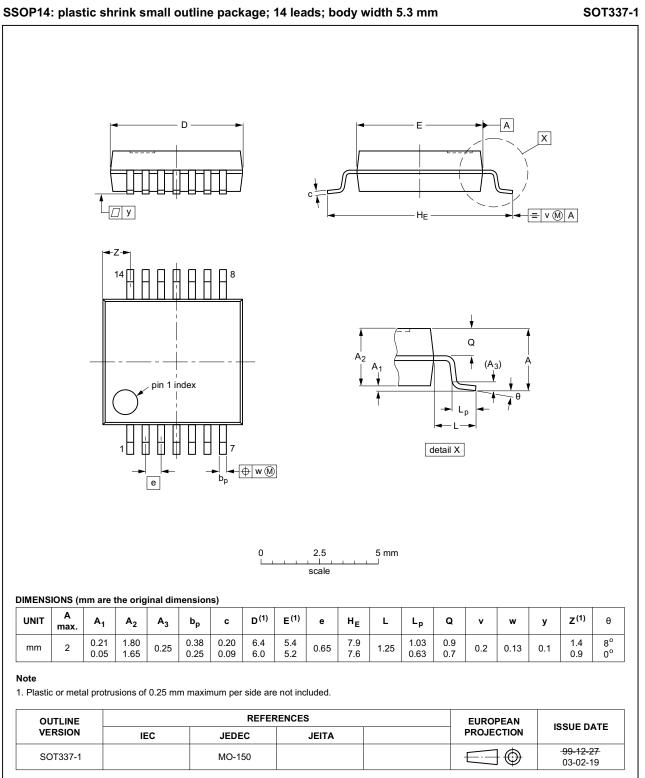


Fig 10. Package outline SOT337-1 (SSOP14)

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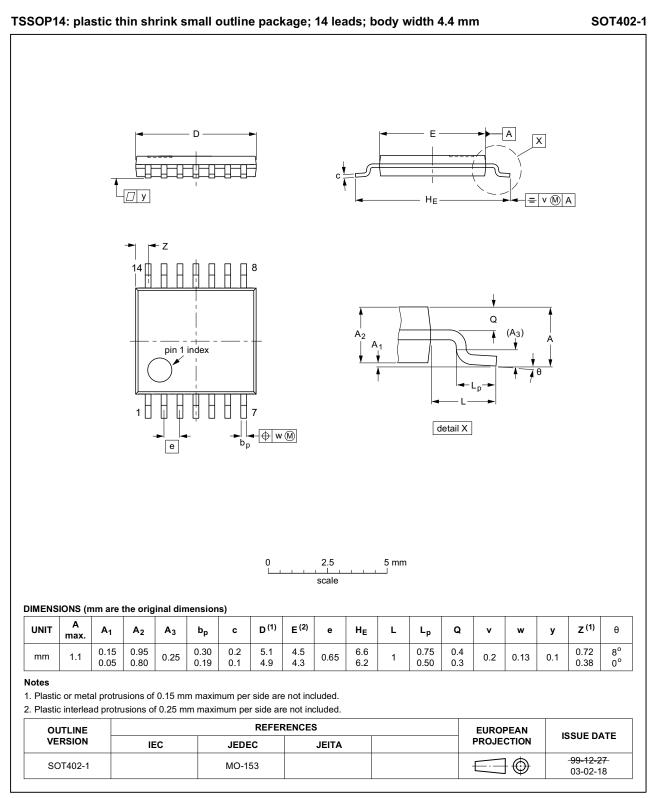


Fig 11. Package outline SOT402-1 (TSSOP14)

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# **13. Abbreviations**

Table 10. Abbreviations		
Acronym	Description	
CMOS	Complementary Metal-Oxide Semiconductor	
DUT	Device Under Test	
ESD	ElectroStatic Discharge	
HBM	Human Body Model	
MM	Machine Model	
TTL	Transistor-Transistor Logic	

# 14. Revision history

#### Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
74HC_HCT126 v.4	20151201	Product data sheet	-	74HC_HCT126 v.3	
Modifications:	Type numbers 74HC126N and 74HCT126N (SOT27-1) removed.				
74HC_HCT126 v.3	20140922	Product data sheet	-	74HC_HCT126_CNV v.2	
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>				
	<ul> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>				
74HC_HCT126_CNV v.2	19901201	Product specification	-	-	

## 15. Legal information

### 15.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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#### Quad buffer/line driver; 3-state

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## 16. Contact information

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Quad buffer/line driver; 3-state

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